

Errors and uncertainties

Ján Šaliga
2017

Errors and uncertainty of measurement

- Metrology – the science on accuracy and precision of measurement.
- Results of measurement may fluctuate and differ from true value.
 - The fluctuation may be caused by instrumentations as well as the properties of measured signal (noise, disturbances) = stochastic error.
 - The difference may be caused mainly but not only inaccurate properties of instrument (electronic circuits, mechanical parts, chemical sensors, ...) = systematic errors
 - Gross errors (have to be always corrected and removed) – caused for example by wrong instrument, broken instrument, wrong reading, wrong calculation, etc.
- We do not know the difference between the true value and results of measurement
- We can only estimate the true value and the difference with some probability – we are not sure what is the true.
- That is why we are speaking about uncertainty of measurement

Errors and uncertainty of measurement

- Uncertainty u is expressed in the form of interval around the estimation of true value x_{est} , where the true value x_{TRUE} lays with some probability P_{required}

$$P(x_{\text{est}} - u < x_{\text{TRUE}} < x_{\text{est}} + u) = P_{\text{required}}$$
- x_{est} and u are needed to be estimated from measurement (measurement results, statistical behavior of results, employed instrumentations, measurement stand, etc.)
- The interval may be also unsymmetrical (given by the distribution of errors)
 - The most common distribution – Gaussian and uniform (the interval is symmetrical)

Uncertainty type A

- Caused by stochastic errors – u_A is calculated from repeated measurement by statistical approach.
- The true value is usually estimated as the mean value calculated from N repeated measurements

$$\bar{x} = \frac{\sum_{i=1}^N x_i}{N}$$
- Standard uncertainty u_A is calculated as the standard deviation of mean value (the probability is 0,68 for Gaussian distribution)

$$u_A = s_{\bar{x}} = \sqrt{\frac{\sum_{i=1}^N (x_i - \bar{x})^2}{N(N-1)}}$$
- Note: the standard uncertainty u_A for single measurement is:

$$u_A = s_{x_i} = \sqrt{\frac{\sum_{i=1}^N (x_i - \bar{x})^2}{(N-1)}}$$

Uncertainty type B

- Uncertainty type B is any uncertainty calculated by a different method than statistic:
 - results from previous measurements,
 - general or empirical knowledge of the behavior of the instruments used,
 - specifications of the manufacturer,
 - calibration certificates,
 - the uncertainty attributed to reference quantity values mentioned in studies, textbooks or norms.

Systematic error and uncertainty type B

- The most common and simple way is calculation from instrument accuracy (max. inaccuracy $\Delta_{\max} x$) specified by producer (see instrument datasheet)
 - Analog instrumentations: $\Delta_{\max} x$ is given in datasheet as a percentage δ_M from the applied measurement range M :

$$|\Delta_{\max} x| \leq \frac{\delta_M}{100} M$$
 - Digital instrumentation: sum of 2 components
 - Percentage δ_x from the result of measurement x
 - The component related to the applied measurement range expressed usually as number of digits K multiplied by the weight of one on the least order of instrument display m_1 :

$$|\Delta_{\max} x| \leq \frac{\delta_x}{100} x + K \cdot m_1$$
- Calculation of standard uncertainty u_B : (for the most probable uniform distribution)

$$u_B = \sigma = \frac{|\Delta_{\max} x|}{\sqrt{3}}$$

Combined uncertainty and propagation of u

- Combined uncertainty u_c = the total uncertainty of measurement

$$u_c = \sqrt{u_a^2 + u_b^2}$$

- If result y is calculated as a combination (function $f(\cdot)$) from N particular measurements a_i of different quantities

$$y = f(a_1, a_2, \dots, a_N)$$

- Then the standard uncertainty of y is: $u_y = \sqrt{\sum_{i=1}^N \left(\frac{\partial f(a_1, a_2, \dots, a_N)}{\partial a_i} \right)^2 u_{a_i}^2}$

- Example: $R=V/I$, $u_y = \sqrt{\left(\frac{\partial R}{\partial V} \right)^2 u_V^2 + \left(\frac{\partial R}{\partial I} \right)^2 u_I^2} = \sqrt{\left(\frac{1}{I} \right)^2 u_V^2 + \left(\frac{V}{I^2} \right)^2 u_I^2}$

Expanded uncertainty U

- Expanded uncertainty U is calculated by multiplication of standard uncertainty u by the coefficient k , $U=ku$
- K is chosen according to required probability that the true values of measured quantity lays with the interval specified by the expanded uncertainty
 - Examples for Gaussian distribution
 - $k=1$, $p=0.68$ (standard uncertainty)
 - $k=3$, $p=0.997$
 - $k=2$, $p=0.99$
 - $k=2/3$, $p=0.5$

Calculation example

- Multimeter Agilent 34405A,
 - measurement of DC voltage, 1V range
 - Condition of measurement according to requirements given by producer
 - Multimeter datasheet: max error = 0.025+0.006 (in percentage from measurement and from range)
- Acquired values:

x_1	x_2	x_3	x_4	x_5	x_6	x_7	x_8	x_9	x_{10}
0,569V	0,561V	0,564V	0,563V	0,567V	0,569V	0,562V	0,564V	0,568V	0,564V

Calculation

- $\bar{x} = 0,5644\text{V}$ $u_A = S_x = 0,000686\text{V}$
- $\Delta_{\text{max}}x = (0,00025 \cdot 0,5644\text{V} + 0,00006 \cdot 1\text{V}) = 0,0002011\text{V}$.
- For uniform distribution of systematic errors:
 $u_B = 0,0002011\text{V} / \sqrt{3} = 0,000116\text{V}$
- Combine standard uncertainty:
 $u_C = \sqrt{u_A^2 + u_B^2} = \sqrt{(0,000686\text{V})^2 + (0,000116\text{V})^2} = 0,000696\text{V}$
- The result of measurement:
 $x_{\text{TRUE}} \in [0,5644\text{V} \pm 0,0007\text{V}]$

Demonstrations

- Simulated multimeter
- myDAQ multimeter with statistics
